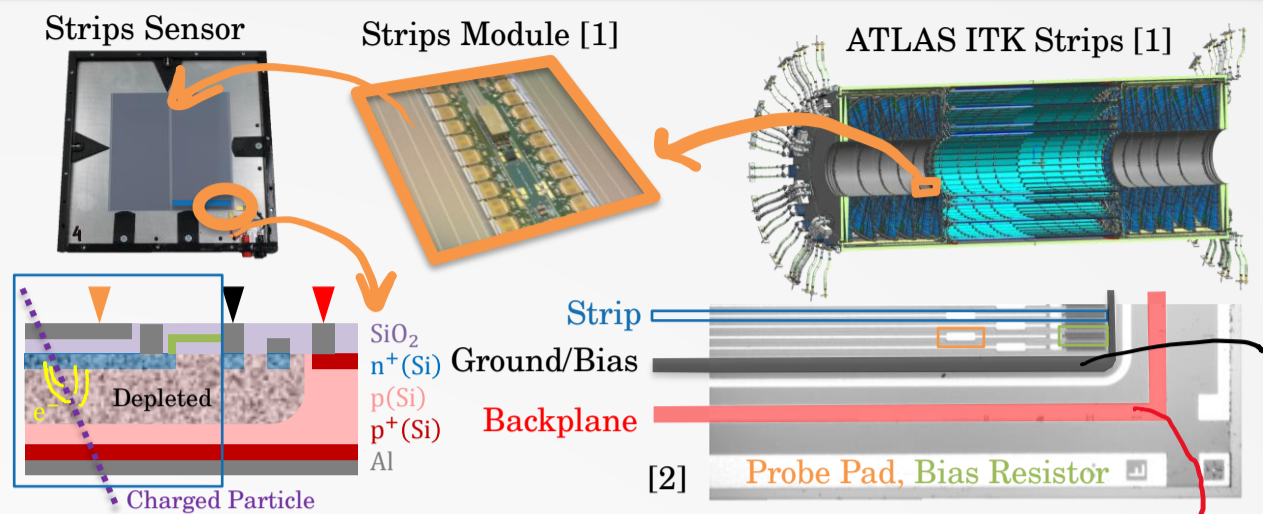


Test and extraction methods for the QC parameters of silicon strip sensors for ATLAS upgrade tracker

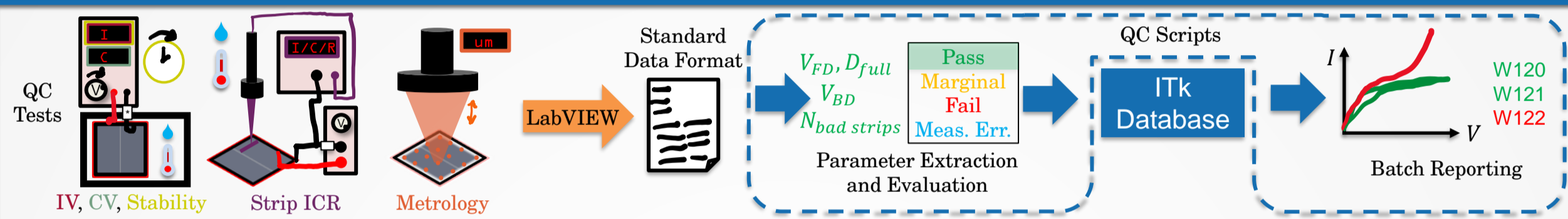
D. Rouso, D. M. Jones, P. Federicova, B. Hommels, A. Affolder, K. Affolder, P.P. Allport, J. Bernabeu, A. Dowling, V. Fadeyev, J. Fernandez-Tejero, A. Fournier, W. George, M. Gignac, L. Gonella, J. Gunnell, K. Hara, S. Hirose, T. Ishii, J. Johnson, S. Kachiguin, N. Kang, I. Kopsalis, J. Kroll, J. Kvasnicka, C. Lacasta, V. Latonova, F. Martinez-Mckinney, M. Mikeskikova, K. Nakamura, K. Saito, C. Solaz, U. Soldevila, M. Ullan, Y. Unno, J. Yarwick

1. Motivation and the ATLAS ITk Strips Sensors

- **ATLAS Inner Tracker (ITk) fully silicon upgrade** comprises **pixel** and **strip** sensors
- **Strips** comprises **22000 sensors** of 8 types (2 barrel and 6 endcap)
- Each sensor to be evaluated for **quality control (QC)** at various institutes with various test setups
- For this, **developed common framework** with common algorithms to objectively **assign pass/fail**, interface with **common database**, and do **reporting**



2. Workflow



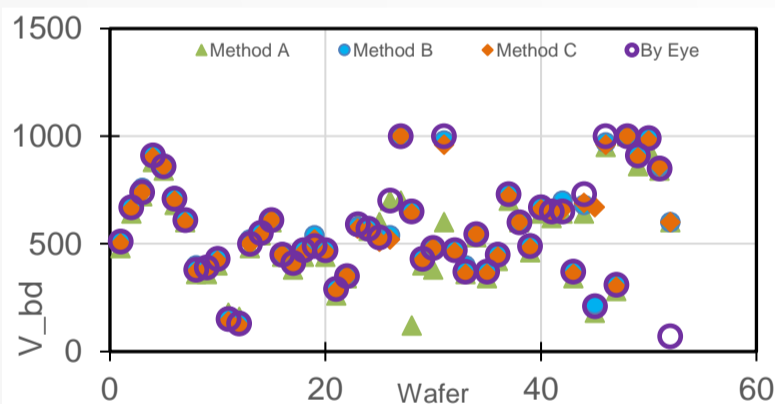
3. Treatment of Current-Voltage (IV) Tests

Method A: (modified from tech spec.)
 V_{bd} is earliest $V_j < -100$ V that satisfies $\left(\frac{1}{3} \sum_{k=j-1}^{j+1} \frac{I_{k+1} - I_k}{V_{k+1} - V_k}\right) \div \left(\frac{I_{k+1} - I_k}{V_{k+1} - V_k}\right)_{min} > 5$
 i.e. avg of 3 local slopes around point divided by min local slope

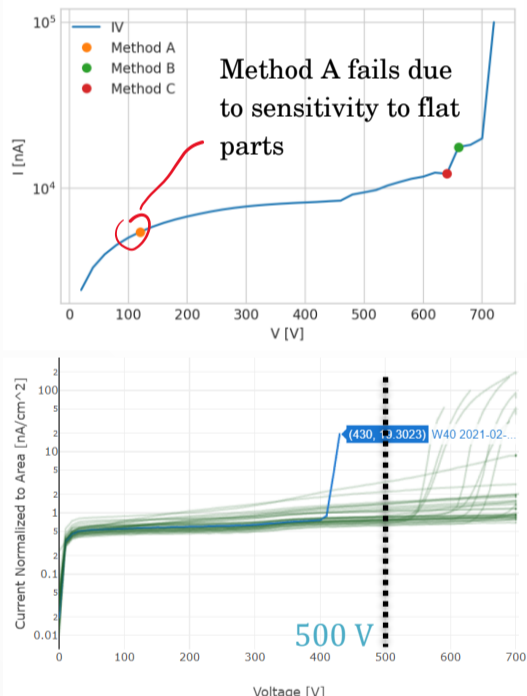
Method B: (modified from [3])
 V_{bd} is earliest V_{j+1} that satisfies $\frac{I_{j+1} - I_j}{V_{j+1} - V_j} \div \frac{I_{j+1}}{V_{j+1}} > 5$
 i.e. local slope at point divided by slope of line from origin to point ("total derivative") > 5 .

Method C: (modified from B)
 V_{bd} is earliest V_{j+1} that satisfies $\frac{I_{j+1} - I_j}{V_{j+1} - V_j} \div \frac{I_{j+1} + I_j}{V_{j+1} + V_j} > 5.5 + \frac{\min(|V| - 500 \text{ V}, 0 \text{ V})}{100 \text{ V}}$
 i.e. B but with averaging, and running threshold to compensate for gradually decreasing total derivative

- Various algorithms for **calculating V_{bd}** explored
- Method B and C equally reliable, but **C is chosen** due to better expected robustness

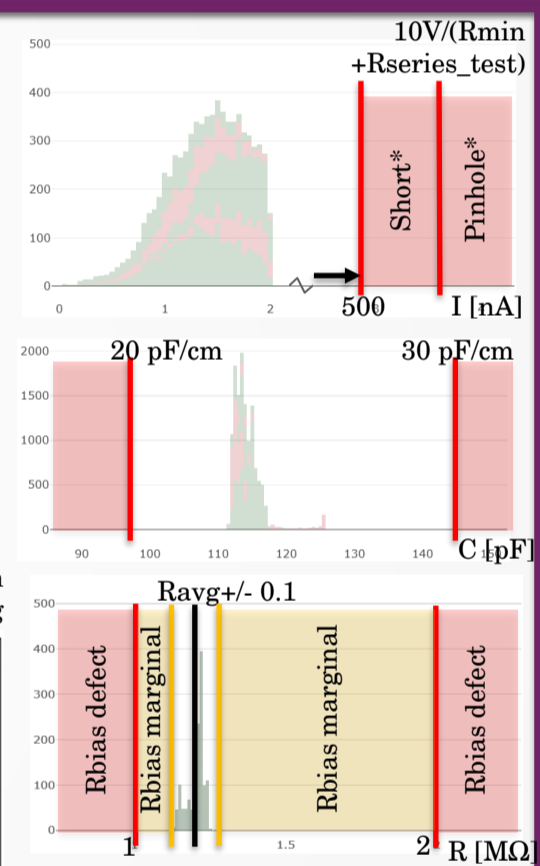


$[I_{max}(V < 500 \text{ V})]$ Max Current $< 100 \text{ nA/cm}^2$
 $[V_{bd}]$ Breakdown Voltage $> 500 \text{ V}$

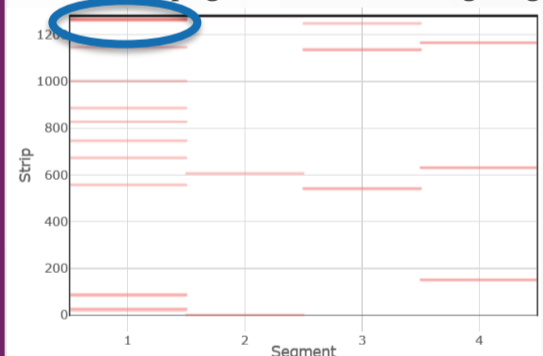


4. Treatment of Individual Strip ICR Tests

- AC-coupled metal strips **probed automatically** to characterize strip RC network and AC current
- Combinations of this info lets scripts **distinguish different failure modes** (metal short, implant break, short, pinhole, Rbias defect), and **measurement issues**



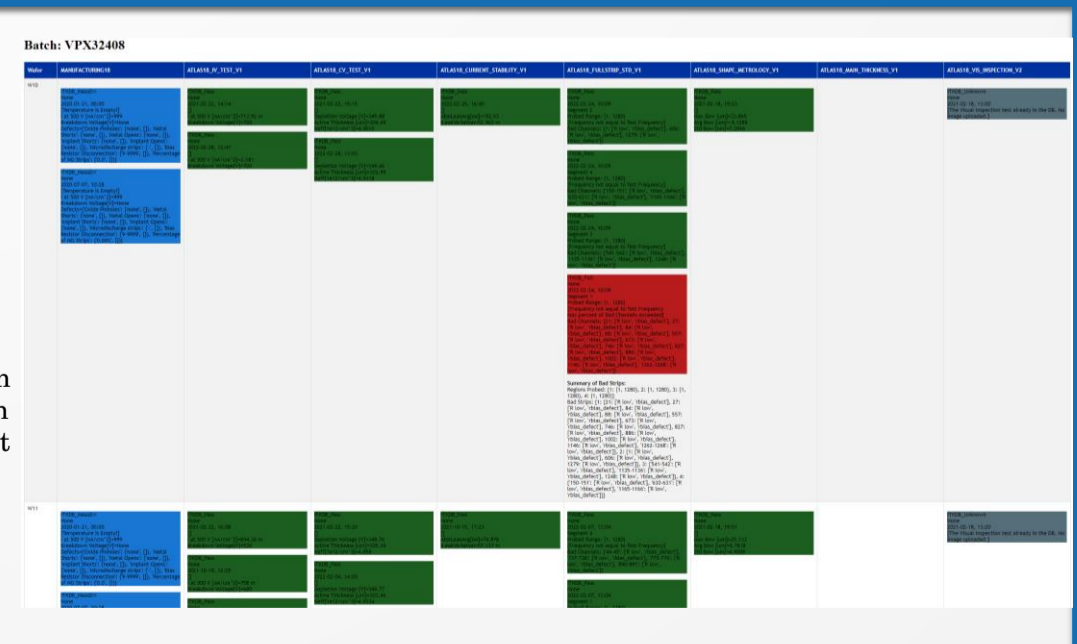
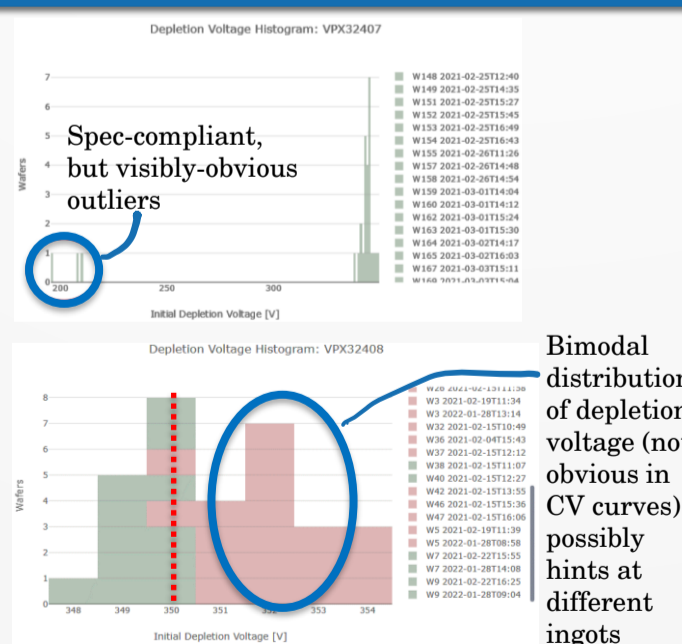
Being able to see geometric correlation helps gives leads in investigating



Total # bad strips $< 1\%$
 # Bad strips in a row < 8

5. Batch Reporting

- QC approval done on **batch-by-batch** basis
- Reports show **interactive diagnostic histograms and plots** by batch
- Allows humans to **visually detect batch issues and outliers** not immediately obvious to an algorithm
- Reporting tool designed to provide a concise table summary and plots of all tests in a batch in a single place for monitoring
- Scripts allow for **direct interactive access to database data** in python for studies



6. Current Status

- Scripts have proven a robust, reliable, and intuitive interface for reporting and monitoring, and have already been instrumental in helping catch subtle issues with sensors and testing
- Have already processed **2500 sensors through preproduction and production in 7 institutes in 5 countries**
- Undergoing continuous development to add new features useful to QC sites **as we enter production**

References & Acknowledgements

[1] CERN-LHCC-2017-005 ; ATLAS-TDR-025
 [2] 10.1016/j.nima.2016.03.042
 [3] 10.1016/S0168-9002(00)01207-9

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